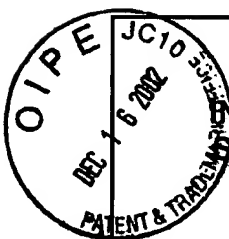


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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet	1	of	1	Application Number	09/854,146
				Filing Date	05/11/2001
				First Named Inventor	Jun Li
				Group Art Unit	2812
				Examiner Name	
				Attorney Docket Number	SPLX.P0050

U.S. PATENT DOCUMENTS

Examiner* Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
VS	1.	5,675,502		Cox	10-07-1997	Abstract, Figs 2, 4 Col. 4-7.
VS	2.	5,841,672		Spyrou et al.	11-24-1998	Abstract, Figs 1-3, Col 1-8

FOREIGN PATENT DOCUMENTS

Examiner* Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code (if known) ⁵				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner* Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
VS	3.	SHEPARD, KL: "Practical Issues of Interconnect Analysis in Deep Submicron Integrated Circuits", Proceeding International Conference on Computer Design VLSI in Computers and Processors, Austin, TX, 12-15 Oct. 1997 pages 532-541	
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Examiner Signature	VUTHE SIEK	Date Considered	1/7/2003
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

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